Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/631,057	DINH ET AL.	
Examiner	Art Unit	_
Quoc A. Tran	2176	

SEARCHED				
Class	Subclass	Date	Examiner	
715	501.1	9/28/2005	B	
455	412.1	9/28/2005	OF.	
707	102	9/28/2005	W.	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	 			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	9/28/2005	at	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search Histoty Printout	9/28/2005	8	
NPL IEEE DataBase see Search History Printout	9/28/2005	K	